

PTO/SB/08B

INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application Number	10/039,344
		Filing Date	December 31, 2001
		First Named Inventor	Satoshi KASAI
		Group Art Unit	2621
		Examiner Name	Shervin K. Nakhjavan
Sheet	of	Attorney Docket Number	01642/LH
NON PATENT LITERATURE DOCUMENTS			
Exam. Initia	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	²
S.N		YIN, Fang-Fang et al, "Computerized detection of masses in digital mammograms: Automated alignment of breast images and its effect on bilateral-subtraction technique," Med. Phys. Vol. 21 No. 3, March 1994, pp. 445-452.	
S.N		MATSUMOTO, Kazuo et al, "Detection Method of Malignant Tumors in DR Images - Iris Filter," Trans. Inst. Electron. Inform. Commun. Eng. D-II, Vol. J75-D-II, No. 3, 1992, pp. 663-670.	
S.N		ISOBE, Yoshiaki et al, "Characteristics of Quot Filter, a Digital Filter Developed for the Extraction of Circumscribed Shadows, and Its Applications to Mammograms," Trans. Inst. Electron. Inform. Commun. Eng. D-II, Vol. J76-D-II, no. 3, 1993, pp. 279-287.	
S.N		SHIMIZU, Akiharu et al, "Minimum Directional Difference Filter for Extraction of Circumscribed Shadows in Chest X-Ray Images and Its Characteristics," Trans. Inst. Electron. Inform. Commun. Eng. D-II, Vol. J76-D-II, No. 2, 1993, pp. 241-249.	
S.N		SPIESBERGER, Wolfgang, "Mammogram Inspection by Computer," IEEE Trans. Biomed Eng BME-26 (4), 1979, pp. 213-219.	
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Examiner Signature	<u>S. Nakhjavan</u>		Date Considered 5-26-05

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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